INTEGRATED CIRCUITS



Product specification Supersedes data of 1996 Oct 08 IC23 Data Handbook

1998 Jan 16



74ABT540

FEATURES

- Octal bus interface
- 3-State buffers
- Live insertion/extraction permitted
- Efficient pinout to facilitate PC board layout
- Output capability: +64mA/–32mA
- Latch-up protection exceeds 500mA per Jedec JC40.2 Std 17
- ESD protection exceeds 2000 V per MIL STD 883 Method 3015 and 200 V per Machine Model
- Power-up 3-State

QUICK REFERENCE DATA

DESCRIPTION

The 74ABT540 high-performance BiCMOS device combines low static and dynamic power dissipation with high speed and high output drive.

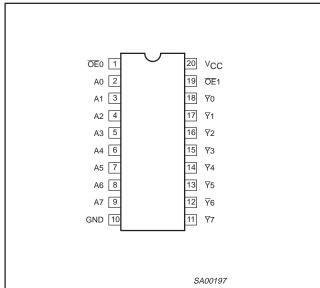
The 74ABT540 device is an octal inverting buffer that is ideal for driving bus lines. The device features input and outputs on opposite sides of the package to facilitate printed circuit board layout.

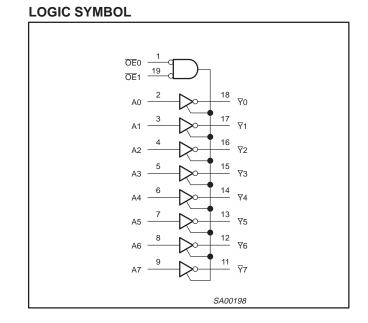
SYMBOL	PARAMETER	CONDITIONS T _{amb} = 25°C; GND = 0V	TYPICAL	UNIT
t _{PLH} t _{PHL}	Propagation delay An to Yn	C _L = 50pF; V _{CC} = 5V	3.1	ns
C _{IN}	Input capacitance	$V_I = 0V \text{ or } V_{CC}$	3	pF
C _{OUT}	Output capacitance	Outputs disabled; V_{O} = 0V or V_{CC}	7	pF
I _{CCZ}	Total supply current	Outputs disabled; $V_{CC} = 5.5V$	50	μA

ORDERING INFORMATION

PACKAGES	TEMPERATURE RANGE	OUTSIDE NORTH AMERICA	NORTH AMERICA	DWG NUMBER
20-Pin Plastic DIP	–40°C to +85°C	74ABT540 N	74ABT540 N	SOT146-1
20-Pin plastic SO	–40°C to +85°C	74ABT540 D	74ABT540 D	SOT163-1
20-Pin Plastic SSOP Type II	–40°C to +85°C	74ABT540 DB	74ABT540 DB	SOT339-1
20-Pin Plastic TSSOP Type I	–40°C to +85°C	74ABT540 PW	74ABT540PW DH	SOT360-1

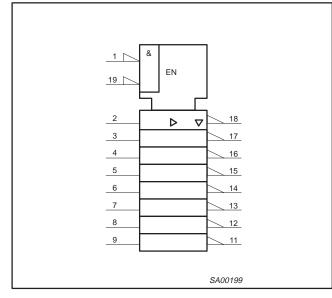
PIN CONFIGURATION





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LOGIC SYMBOL (IEEE/IEC)



PIN DESCRIPTION

PIN NUMBER	SYMBOL	NAME AND FUNCTION		
2, 3, 4, 5, 6, 7, 8, 9	A0 – A7	Data inputs		
18, 17, 16, 15, 14, 13, 12, 11	$\overline{Y}0 - \overline{Y}7$	Data outputs		
1, 19	<u>OE</u> 0, <u>OE</u> 1	Output enables		
10	GND	Ground (0V)		
20	V _{CC}	Positive supply voltage		

FUNCTION TABLE

	INPUTS		OUTPUTS
OE0	OE1	An	Ϋ́n
L L X H	L L H X	L H X X	H L Z Z

H = High voltage level

L = Low voltage level

X = Don't care Z = High impedance "off" state

ABSOLUTE MAXIMUM RATINGS^{1, 2}

SYMBOL	PARAMETER	CONDITIONS	RATING	UNIT	
V _{CC}	DC supply voltage		-0.5 to +7.0	V	
I _{IK}	DC input diode current	V ₁ < 0	-18	mA	
VI	DC input voltage ³		-1.2 to +7.0	V	
I _{OK}	DC output diode current	V _O < 0	-50	mA	
V _{OUT}	DC output voltage ³	output in Off or High state	-0.5 to +5.5	V	
I _{OUT}	DC output current	output in Low state	128	mA	
T _{stg}	Storage temperature range		–65 to 150	°C	

NOTES:

1. Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150°C.
The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIM	UNIT	
		Min	Мах	1
V _{CC}	DC supply voltage	4.5	5.5	V
VI	Input voltage	0	V _{CC}	V
V _{IH}	High-level input voltage	2.0		V
V _{IL}	Low-level Input voltage		0.8	V
I _{ОН}	High-level output current		-32	mA
I _{OL}	Low-level output current		64	mA
$\Delta t/\Delta v$	Input transition rise or fall rate	0	10	ns/V
T _{amb}	Operating free-air temperature range	-40	+85	°C

DC ELECTRICAL CHARACTERISTICS

					LIMITS				
SYMBOL	PARAMETER	TEST CONDITIONS	Tai	_{mb} = +25	°C	T _{amb} =	-40°C 85°C	UNIT	
			Min	Тур	Max	Min	Max	ax	
V _{IK}	Input clamp voltage	$V_{CC} = 4.5V; I_{IK} = -18mA$		-0.9	-1.2		-1.2	V	
		V_{CC} = 4.5V; I_{OH} = –3mA; V_{I} = V_{IL} or V_{IH}	2.5	2.9		2.5		V	
V _{OH}	High-level output voltage	V_{CC} = 5.0V; I_{OH} = –3mA; V_{I} = V_{IL} or V_{IH}	3.0	3.4		3.0		V	
		V_{CC} = 4.5V; I_{OH} = –32mA; V_{I} = V_{IL} or V_{IH}	2.0	2.4		2.0		V	
V _{OL}	Low-level output voltage	V_{CC} = 4.5V; I_{OL} = 64mA; V_{I} = V_{IL} or V_{IH}		0.42	0.55		0.55	V	
l _l	Input leakage current	V_{CC} = 5.5V; V_I = GND or 5.5V		±0.01	±1.0		±1.0	μA	
I _{OFF}	Power-off leakage current	V_{CC} = 0.0V; $V_{I}~~or~V_{O} \leq 4.5V$		±5.0	±100		±100	μA	
I _{PU} /I _{PD}	Power-up/down 3-State output current ³	$C_{CC} = 2.1V; V_{O} = 0.5V; V_{I} = GND \text{ or } V_{CC};$ $D_{DE} = Don't \text{ care}$		±5.0	±50		±50	μA	
I _{OZH}	3-State output High current	$V_{CC} = 5.5 \text{V}; \text{V}_{O} = 2.7 \text{V}; \text{V}_{I} = \text{V}_{IL} \text{ or } \text{V}_{IH}$		5.0	50		50	μA	
I _{OZL}	3-State output Low current	V_{CC} = 5.5V; V_{O} = 0.5V; V_{I} = V_{IL} or V_{IH}		-5.0	-50		-50	μA	
I _{CEX}	Output High leakage current	V_{CC} = 5.5V; V_{O} = 5.5V; V_{I} = GND or V_{CC}		5.0	50		50	mA	
Ι _Ο	Output current ¹	$V_{CC} = 5.5V; V_O = 2.5V$	-50	-100	-180	-50	-180	mA	
I _{CCH}		V_{CC} = 5.5V; Outputs High, V_{I} = GND or V_{CC}		50	250		250	μA	
I _{CCL}	Quiescent supply current	V_{CC} = 5.5V; Outputs Low, V_{I} = GND or V_{CC}		24	30		30	mA	
I _{CCZ}		V_{CC} = 5.5V; Outputs 3-State; V _I = GND or V _{CC}		50	250		250	μΑ	
		Outputs enabled, one input at 3.4V, other inputs at V_{CC} or GND; V_{CC} = 5.5V		0.5	1.5		1.5	mA	
ΔI_{CC}	Additional supply current per input pin ²	Outputs 3-State, one data input at 3.4V, other inputs at V_{CC} or GND; V_{CC} = 5.5V		0.5	50		50	μA	
		Outputs 3-State, one enable input at 3.4V, other inputs at V_{CC} or GND; V_{CC} = 5.5V		0.5	1.5		1.5	mA	

NOTES:

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Not more than one output should be tested at a time, and the duration of the test should not exceed one second.
This is the increase in supply current for each input at 3.4V.
This parameter is valid for any V_{CC} between 0V and 2.1V, with a transition time of up to 10msec. From V_{CC} = 2.1V to V_{CC} = 5V ± 10% a transition time of up to 100µsec is permitted.

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Product specification

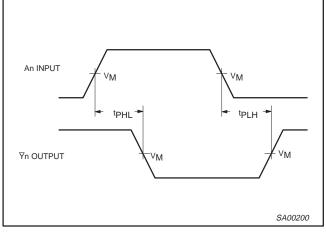
AC CHARACTERISTICS

GND = 0V; $t_R = t_F = 2.5ns$; $C_L = 50pF$, $R_L = 500\Omega$

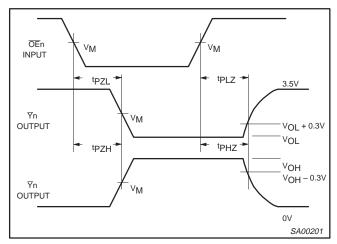
SYMBOL	PARAMETER	WAVEFORM	T _a V	_{imb} = +25° CC = +5.0	C V	$T_{amb} = -40^{\circ}$ $V_{CC} = +5^{\circ}$	UNIT	
			Min	Тур	Мах	Min	Max	
t _{PLH} t _{PHL}	Propagation delay An to Yn	1	1.0 1.0	2.9 3.1	4.1 4.3	1.0 1.0	4.8 4.8	ns
t _{PZH} t _{PZL}	Output enable time to High and Low level	2	1.1 1.1	4.1 4.6	4.9 5.8	1.1 1.1	5.9 6.4	ns
t _{PHZ} t _{PLZ}	Output disable time from High and Low level	2	1.5 1.2	3.6 2.9	6.8 5.7	1.5 1.2	7.3 6.2	ns

AC WAVEFORMS

 V_{M} = 1.5V, V_{IN} = GND to 3.0V

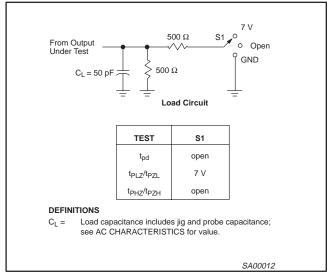


Waveform 1. Waveforms Showing the Input (An) to Output (Yn) Propagation Delays



Waveform 2. Waveforms Showing the 3-State Output Enable and Disable Times

TEST CIRCUIT AND WAVEFORMS

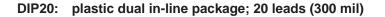


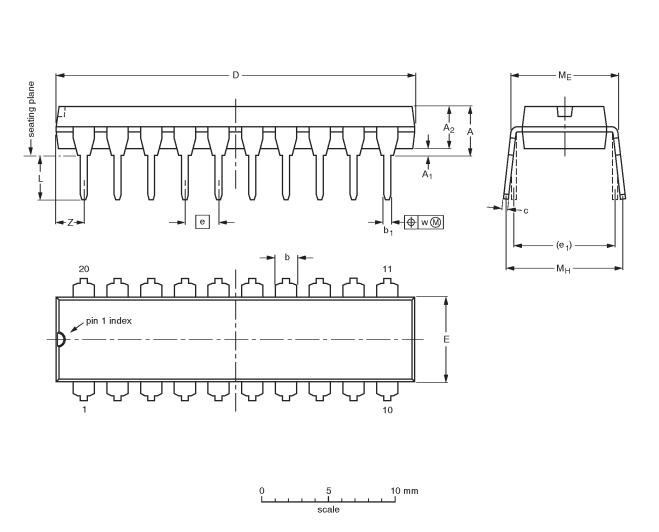
Product specification

SOT146-1

Octal buffer, inverting (3-State)

74ABT540





DIMENSIONS (inch dimensions are derived from the original mm dimensions)

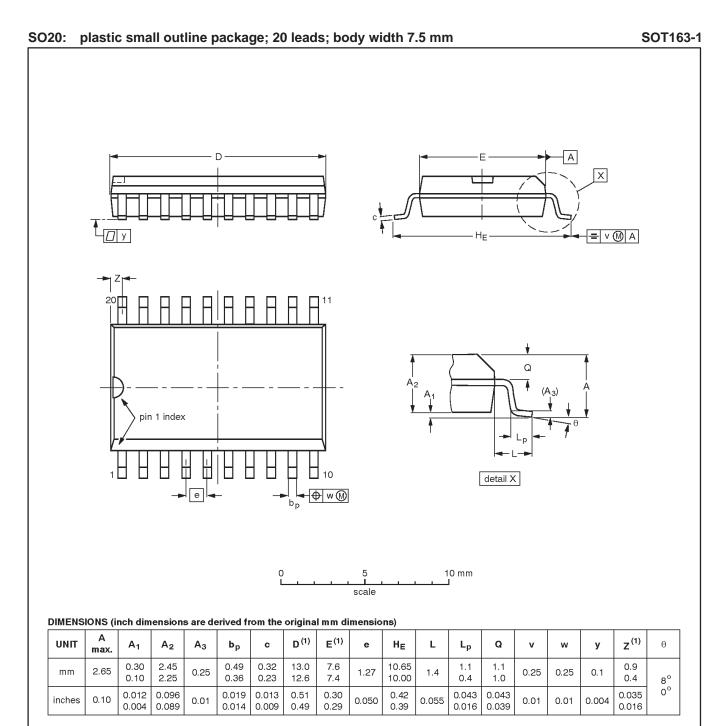
UNIT	A max.	A ₁ min.	A ₂ max.	b	b ₁	c	D ⁽¹⁾	E ⁽¹⁾	e	e ₁	L	M _E	M _H	w	Z ⁽¹⁾ max.
mm	4.2	0.51	3.2	1.73 1.30	0.53 0.38	0.36 0.23	26.92 26.54	6.40 6.22	2.54	7.62	3.60 3.05	8.25 7.80	10.0 8.3	0.254	2.0
inches	0.17	0.020	0.13	0.068 0.051	0.021 0.015	0.014 0.009	1.060 1.045	0.25 0.24	0.10	0.30	0.14 0.12	0.32 0.31	0.39 0.33	0.01	0.078

Note

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

OUTLINE		REFER	RENCES	EUROPEAN			
VERSION	IEC	JEDEC	EIAJ	PROJECTION	ISSUE DATE		
SOT146-1			SC603		-92-11-17 95-05-24		

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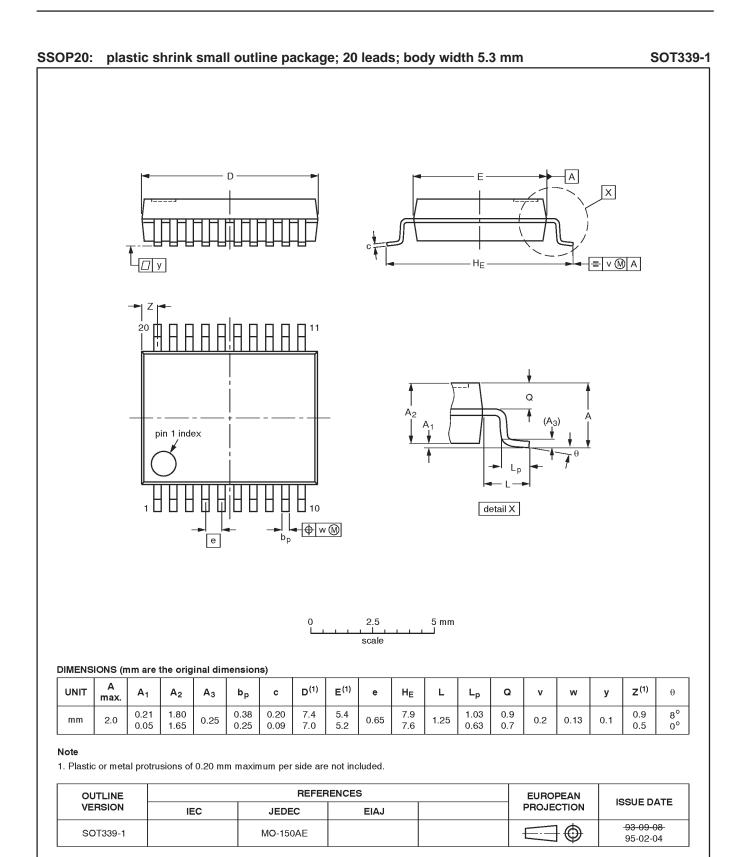


Note

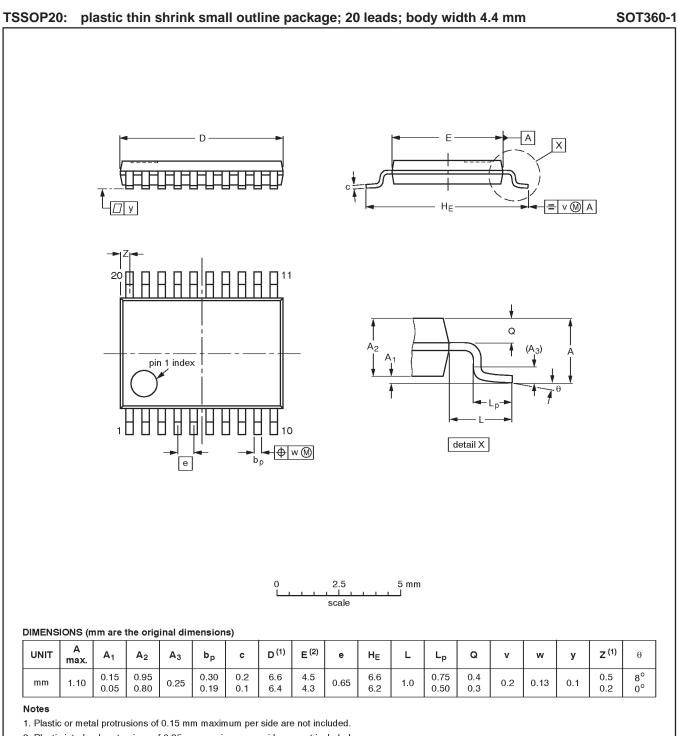
1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

OUTLINE		REFER	REFERENCES		EUROPEAN	ISSUE DATE	
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE	
SOT163-1	075E04	MS-013AC				-92-11-17 95-01-24	

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2. Plastic interlead protrusions of 0.25 mm maximum per side are not included.

OUTLINE		REFER	ENCES	EUROPEAN	ISSUE DATE	
VERSION	IEC	JEDEC	EIAJ	PROJECTION	ISSUE DATE	
SOT360-1		MO-153AC			-93-06-16- 95-02-04	

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Data sheet status

Data sheet status	Product status	Definition ^[1]
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.
Preliminary specification	Qualification	This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make chages at any time without notice in order to improve design and supply the best possible product.
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[1] Please consult the most recently issued datasheet before initiating or completing a design.

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